Client/Matter: 012237-0281180

IN THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

1. (Previously Presented) An apparatus for examining a surface, comprising:

a polarization analyser element placed in a path of a light beam reflected by the surface, the polarization analyser element constructed and arranged to alternately transmit a crossed polarization state and a parallel polarization state;

a digital image acquisition device disposed in the path of the beam reflected by the surface downstream of the polarization analyser element; and

a processing unit configured to calculate a brightness and an intensity of a plurality of points of the surface from pixels of at least two images of the surface;

wherein the apparatus does not contact the surface.

- 2. (Previously Presented) An apparatus according to Claim 1, further comprising a source of polarized light configured to emit a beam incident on the surface to be examined.
- 3. (Previously Presented) An apparatus according to Claim 2, wherein the light emanating from the source is substantially isotropic.
- 4. (Previously Presented) An apparatus according to Claim 2, wherein the light emanating from the source is substantially white.
- 5. (Previously Presented) An apparatus according to Claim 2, wherein a spectrum of the light emanating from the source is substantially the same as a solar spectrum.
- 6. (Previously Presented) An apparatus according to Claim 1, wherein the polarization analyser element comprises a first transmitter configured to transmit crossed polarization and a second transmitter configured to transmit parallel polarization, the first and second transmitters being alternatively active.
- 7. (Previously Presented) An apparatus according to Claim 6, wherein the polarization analyser element is rotatable.

Client/Matter: 012237-0281180

8. (Previously Presented) An apparatus according to Claim 6, the polarization analyser element further comprises an electrical switching component.

- 9. (Previously Presented) A process for the non-contact examination of a keratinous surface, comprising:
- (i) analysing crossed and parallel polarizations of a light beam reflected by the surface;
- (ii) taking digital images of the crossed and parallel polarizations of the reflected beam; and
- (iii) calculating a brightness and an intensity of a plurality of points of the surface from pixels of at least two images of the surface.
- 10. (Previously Presented) A process according to Claim 9, wherein the surface is uneven.
- 11. (Previously Presented) A process according to Claim 9, wherein the digital images are monochromatic digital images.
- 12. (Previously Presented) A process according to Claim 9, wherein the digital images are polychromatic digital images.
- 13. 14. (Cancelled).
- 15. (Previously Presented) An apparatus for examining a surface comprising:

a source of polarized light constructed and arranged to emit a beam incident on the surface to be examined, a spectrum of the light being substantially the same as a solar spectrum;

a polarization analyzer element placed in a path of a light beam reflected by the surface;

a digital image acquisition device disposed in the path of the beam reflected by the surface downstream of the polarization analyzer element; and

a processing unit configured to calculate a brightness and an intensity of a plurality of points of the surface from pixels of at least two images of the surface;

Client/Matter: 012237-0281180

wherein the apparatus does not contact the surface.

16. (Previously Presented) An apparatus for examining a surface comprising:

an optical element selected from the group consisting of an orientable polarisation analyser element and a polarizing splitter cube placed in a path of a light beam reflected by the surface;

a camera configured to take digital images, the camera being placed in the path of the beam reflected by the surface downstream of the polarization analyser element; and

a processing unit configured to calculate a brightness and an intensity of a plurality of points of the surface from pixels of at least two images of the surface; wherein the apparatus does not contact the surface.

- 17. (Previously Presented) An apparatus according to Claim 15 or 16, further comprising a source of polarized light configured to emit a beam incident on the surface to be examined.
- 18. (Previously Presented) An apparatus according to Claim 17, wherein the light emanating from the source is substantially isotropic.
- 19. (Previously Presented) An apparatus according to Claim 15 or 16, wherein the light emanating from the source is substantially white.
- 20. (Previously Presented) An apparatus according to Claim 15 or 16, wherein a spectrum of the light emanating from the source is substantially the same as a solar spectrum.
- 21. (Previously Presented) An apparatus according to Claim 15 or 16, wherein the analyser comprises a first transmitter configured to transmit the crossed polarization and a second transmitter configured to transmit the parallel polarization, the first and second transmitters being alternatively active.
- 22. (Previously Presented) An apparatus according to Claim 21, wherein the analyser is rotatable.

Client/Matter: 012237-0281180

23. (Previously Presented) An apparatus according to Claim 21, wherein the analyser further comprises an electrical switching component.

- 24. (Previously Presented) The process of Claim 9, wherein the process is performed by a computer.
- 25. (Previously Presented) A computer-readable medium bearing a program code embodied thereon for performing the process of Claim 9.
- 26. (Previously Presented) An apparatus for examining a surface, comprising:

a polarization analyser element placed in a path of a light beam reflected by the surface, the polarization analyser element constructed and arranged to alternately transmit a crossed polarization state and a parallel polarization state;

a digital image acquisition device disposed in the path of the beam reflected by the surface downstream of the polarization analyser element; and

a processing unit configured and arranged to calculate a brightness and color information for a plurality of points of the surface from pixels of at least two images of the surface;

wherein the apparatus does not contact the surface.